

4/11/05

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-2481		SERIAL NO. 10/820,568	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Leonard Forbes		10/820,568	
					FILING DATE April 7, 2004		GROUP 2018 2827	
U.S. PATENT DOCUMENTS								
*Examine Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
W	AA	5,825,687	10/1998	Yin				
W	AB	5,285,687	2/1994	Ringle et al.				
	AC							
	AD							
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	AH							
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FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER <i>V. Nguyen</i>				DATE CONSIDERED <i>7/20/05</i>				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M21-241		SERIAL NO. 10220440	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Leonard Forbes		10/820,568	
				FILING DATE April 7, 2004		GROUP 7827	
U.S. PATENT DOCUMENTS 4/7/2004							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
LN	AA	2003/0048656	3/2003	Forbes			
LN	AB	2003/0048657	3/2003	Forbes			
LN	AC	4,813,160	11/2004	Forbes			
	AD						
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	AI						
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
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OTHER REFERENCES (including Author, Title, Date, Foreign Pages, Etc.)							
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				FILING DATE April 7, 2004		GROUP 2827	
U.S. PATENT DOCUMENTS 4/7/2004							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
W	AA	6,208,555	3/2001	Noble			
W	AB	2004/0026697	2/2004	Forbes			
W	AC	2003/0214840	11/2003	Forbes			
W	AD	2003/0015907	3/2003	Forbes			
W	AE	2001/0015907	8/2001	Noble			
	AF						
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M722-2481		SERIAL NO. 10/820,568	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Leonard Forbes		10/820,568	
				FILING DATE April 7, 2004		GROUP 2827	
U.S. PATENT DOCUMENTS 4/7/2004							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
W	AA	6,603,391	8/2003	Forbes, Leonard			
W	AB	6,449,116	9/2002	Noble, Wendell P.			
W	AC	6,097,533	5/2000	Reedy et al.			
	AD						
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	AI						
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
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OTHER REFERENCES (including Author, Title, Date, Pending Pages, etc.)							
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-2481	PRIORITY SERIAL NO. 10469-804			
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Leonard Forbes	10/820, 368			
				PRIORITY FILING DATE July 10, 2003	PRIORITY GROUP 2829			
U.S. PATENT DOCUMENTS (7/10/2003)								
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate		
W	AA	6,128,218	10/03/00	Noble, Jr. et al.				
W	AB	5,825,687	10/20/98	Yin				
W	AC	6,287,913 B1	09/11/01	Agnello et al.				
W	AD	5,754,468	05/19/98	Hobson				
W	AE	6,104,045	08/15/00	Forbes et al.				
W	AF	6,225,165 B1	05/01/01	Noble, Jr. et al.				
W	AG	6,342,718 B1	01/29/02	Noble				
W	AH	6,194,759 B1	02/20/01	Sano et al.				
W	AI	6,459,113 B1	10/01/02	Moribara et al.				
W	AJ	2002/0028550 A1	03/07/02	Moribara et al.				
W	AK	6,011,728	01/04/00	Batson et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Abstract	
							Yes	No
W	AL	10-335488	12/1988	Japan				X
W	AM	JP02001308298 A	11/02/01	Japan			X	
	AN							
	AO							
	AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
W	AR	Lago et al., "Advanced SRAM technology - the rate between 4T and 6T cells," Abstract (Web address - http://photo.ei.org).						
		Technical Digest - Proceedings of the 1996 IEEE International Electron Devices Meeting Dec. 8-11, 1996.						
W	AS	Noda et al., "A 1.9- μ m Loadless CMOS Four-Transistor SRAM Cell in a 0.18- μ m Logic Technology", 1998.						
		ULSI Device Development Laboratories, NEC Corporation, Japan, 5 pages.						
	AT							
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M22-2481		PRIORITY SERIAL NO. 4845558	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Leonard Forbes		60/820,568 o/c	
					PRIORITY FILING DATE July 10, 2003		PRIORITY GROUP 2878 2827	
U.S. PATENT DOCUMENTS								
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate		
W	AA	6,184,588	2/2001	Kim et al.				
W	AB	5,774,392	6/1998	Kraus et al.				
	AC	6,212,102	4/2001	Georgakos et al.				
	AD	6,265,266	7/2001	Dejerfett et al.				
	AE	5,388,068	2/1995	Ghoshal et al.				
	AF	5,754,010	5/1998	Ceravella et al.				
	AG	6,519,197 B2	2/11/2003	Forbes				
	AH	2003/0076721 A1	4/24/2003	Forbes				
	AI	6,275,433 B1	8/14/2001	Forbes				
W	AJ	6,448,601 B1	9/10/2002	Forbes et al.				
W	AK	6,090,648	7/18/2000	Reedy et al.				
FOREIGN PATENT DOCUMENTS								
	Document Number	Date	Country	Class	Subclass	Abstract		
						Yes	No	
	AL							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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